



Report No .:

EMC 1606024

File reference No.: 2016-06-18

Applicant:

Product:

POWERBANK WITH CHARGING STATION

Brand Name:

N/A

Model No .:

98820

Test Standards:

EN 55022: 2010+AC:2011

EN61000-3-2:2014

EN 55024: 2010+A1:2015

EN 61000-3-3: 2013

Test result:

The EMC testing has been performed on the submitted samples

and found in compliance with council EMC Directive

2014/30/EU.

Approved By

Terry Tang

Manager

Dated:

June. 18, 2016

Results appearing herein relate only to the sample tested The technical reports is issued errors and omissions exempt and is subject to withdrawal at

# SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519, 5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen, Guangdong China

Tel (755) 83448688

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Email: info@timeway-lab.com

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# **Special Statement:**

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

The testing quality system of our laboratory meets with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

# **CNAS-LAB Code: L2292**

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

# FCC-Registration No.: 899988

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.:899988.

# IC- Registration No.: IC5205A-01

The EMC Laboratory has been registered and fully described in a report filed with the (IC) Industry Canada. The acceptance letter from the IC is maintained in our files. Registration No.: IC 5205A-01.

# VCCI- Registration No.: R-3015 and C-3332

The EMC Laboratory has been registered and fully described in a report filed with the (VCCI) Voluntary Control Council for Interference. The acceptance letter from the VCCI is maintained in our files. Registration IC No.: R-3015 and C-3332

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Photo of testing 42

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#### 1.0 General Details

#### 1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

#### **Test Location**

#### All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

No tests were sub-contracted.

#### **1.2** Applicant Details

Applicant:

Address:

Telephone:

Fax:

Manufacturer:

Address:

Telephone

Fax:

# **1.3** Description of EUT

Product: POWERBANK WITH CHARGING STATION

Brand Name: N/A Model Number: 98820 Adding Model Number: --

Rating: Input:DC5V, Output:DC5V, 1A

Remark: ---

# **1.4** Submitted Sample(s)

1 Sample

# 1.5 Test Duration

2016-06-01 to 2016-06-18

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# Additional information of EUT

	Submitted	Not Available
User Manual	$\boxtimes$	
Part List		
Circuit Diagram		
Printed circuit board[PCB] Layout		
Block Diagram		

1.7 Test Engineer

The sample(s) tested by

Print Name: Leo Lau/ Enginee

This test report is not valid without personnel's signatures of SHENZHEN TIMEWAY TESTING LABORATORIES

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# 2.0 List of Measurement Equipment

#### 2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESH3	860905/006	RS	2016.06.11	1Year
Spectrum Analyzer	ESA-L1500A	US37451154	HP	2016.06.11	1Year
PULSE LIMITER	ESH3-Z2	100281	RS	2016.06.11	1Year
LISN	ESH3-Z5	100294	RS	2016.06.11	1Year
LISN	ESH3-Z5	100253	RS	2016.06.11	1Year

#### 2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESVD	100008	RS	2016.06.11	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer	8595E	3441A00893	HP	2016.06.11	1Year
Amplifier	8447D	2727A05017	HP	2016.06.11	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2016.06.11	1Year

#### 2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test System	PACS-1	72305	CI	2015.09.29	1Year
5K VA AC Power Source	5001iX	56060	CI	2015.09.29	N/A

#### 2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2016.06.11	1Year

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#### 2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2016.06.11	1Year
Power Meter	NRVS		RS	2016.06.11	1Year
Voltage Probe	URV5-Z2	100012	RS	2016.06.11	1Year
Voltage Probe	URV5-Z2	100013	RS	2016.06.11	1Year
Power Amplifier	150W1000	300999	AR	2016.06.11	1Year
Power Amplifier	25S1G4AM1	305993	AR	2016.06.11	1Year
Field Probe	CBL6111C	2576	Holaday	2016.06.11	1Year
Bilog Antenna	MCDC		Chase	2016.06.11	1Year

# 2.6 Electrical Fast Transient/Burst (EFT/B) Immunitytest

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2016.06.11	1Year
Power Source	MV2616	0104-14	EM TEST	2016.06.11	1Year

#### 2.7 Surge Test

				Calibration Date	Calibration
Name	Model No.	Serial No.	Manufacturer	Candiation Date	Cycle
Ultra Compact	UCS 500			2016.06.11	
Simulator	M4	0304-42	EM TEST		1Year
Power Source	MV2616	0104-14	EM TEST	2016.06.11	1Year

#### 2.8 Conducted Immunity Test

					Calibration	Calibration
Name		Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous	Wave					
Simulator		CWS 500C	0407-05	EM TEST	2016.06.11	1 Year

# 2.9 Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave	UCS 500 M4	0304-42		2016.06.11	
Simulator	0CS 300 WI4	0304-42	EM TEST		1 Year
Power Source	MV 2616	0104-14		2016.06.11	
Network		0104-14	EM TEST		1 Year
Current Transformer	MC2630		EM TEST	2016.06.11	1 Year

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gnetic Coil MS100	0304-42	EM TEST	2015.06.11	1 Year	
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#### Voltage Dips/Interruption Immunity Test 2.10

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact				2016.06.11	
Simulator	UCS 500 M4	0304-42	EM TEST		1Year
Power Source	MV2616	0104-14	EM TEST	2016.06.11	1Year

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#### 3.0 Technical Details

#### 3.1 Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility[ EMS] tests for CE Marking

#### 3.2 Test Standards

	Test Standards			
EN 55022: 2010	Limits and methods of measurement of	f radio disturbance characteristics of		
EN 33022. 2010	nformation technology equipment			
EN61000-3-2:2014	Electromagnetic compatibility(EMC)- emissions(equipment input current $\leq$	Part 3-2:Limits-Limits for harmonic current 16A per phase)		
	Electromagnetic compatibility (EMC	C)- Part 3-3:Limits-Limitation of voltage		
EN 61000-3-3:2013	changes, Voltage fluctuations and flick	er in public low-voltage supply systems. For		
EN 01000-3-3.2013	equipment with rated current ≤16A per phase and not subject to conditional			
	connection			
EN	Information technology equipment —	Immunity characteristics — Limits and		
55024:2010+A1:2015	methods of measurement			
	EN 61000-4-2:2009	Electrostatic discharge		
	EN 61000-4-3:2006	RF field strength susceptibility		
	EN 61000-4-4:2012	Electrical Fast transients		
	EN 61000-4-5:2014	Surge		
	EN 61000-4-6:2009 Conducted susceptibility			
	EN 61000-4-8:2010	Power-frequency Magnetic Field		
	EN 61000-4-11:2004	Dips/Voltage Interruption Variation		

# 33 Performance Criteria

Criterion	Description		
A No change in operational mode or degradation of performance outsing specification and no change in stored parameters.			
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.		
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.		

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#### 3.4 Test standards and Results Summary Tables

Test Condition	Test Requirement	Test Method	Test Result
	EMISSION Results Sum	mary	
Conducted Emission on AC Mains,	EN 55022: 2010+AC:2011	EN 55022: 2010+AC:2011	N/A
150KHz to 30MHz			IN/A
Conducted Emission on at	EN 55022: 2010+AC:2011	EN 55022: 2010+AC:2011	
telecommunication ports,			N/A
150KHz to 30MHz			
Radiated Emissions,	EN 55022: 2010+AC:2011	EN 55022: 2010+AC:2011	D
30MHz to 1GHz			Pass
Harmonic Emissions on AC supply	EN61000-3-2:2014	EN61000-3-2:2014	N/A
Voltage fluctuations on AC supply	EN 61000-3-3: 2013	EN 61000-3-3: 2013	N/A
	IMMUNITY Results Sum	nmary	
Electrostatic Discharge	EN 55024: 2010+A1:2015	EN 61000-4-2: 2009	Pass
Electrical Fast transients	EN 55024: 2010+A1:2015	EN 61000-4-4: 2012	N/A
/Burst Immunity			IN/A
RF field strength susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-3: 2006	Pass
Surge	EN 55024: 2010+A1:2015	EN 61000-4-5: 2014	N/A
Conducted susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-6: 2009	N/A
Power-frequency Magnetic Field	EN 55024: 2010+A1:2015	EN61000-4-8: 2010	N/A
Dips/Voltage Interruption Variation	EN 55024: 2010+A1:2015	EN 61000-4-11: 2004	N/A

Note: N/A-Not applicable

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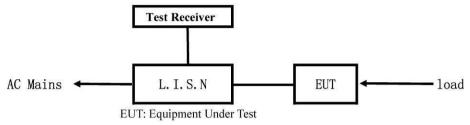
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# 4.0 Electromagnetic Interference Test results

#### **4.1** Power line Conducted Emission Test

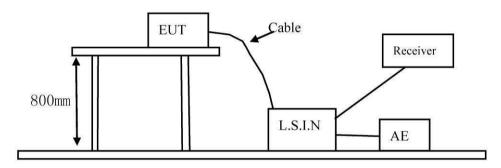
#### 4.1.1 Schematics of the test



#### 4.1.2 Test Method:

The test was performed in accordance with EN 55022: 2010+AC:2011

#### **Block diagram of Test setup**



#### 4.1.3 Power line conducted Emission Limit

	Limits dB( μ V)					
Frequency(MHz)	Class A I	Equipment	Class B Equipment			
2	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level		
$0.15 \sim 0.50$	79.0	66.0	66.0~56.0*	56.0~46.0*		
$0.50 \sim 5.00$	73.0	60.0	56.0	46.0		
5.00 ~ 30.00	73.0	60.0	60.0	50.0		

Notes:

- 1. \*decreasing linearly with logarithm of frequency.
- 2. The lower limit shall apply at the transition frequencies

#### 4.1.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

#### Remark:

Calculated measurement uncertainty=3.6dB

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# A: Conducted Emission on Live Terminal (150kHz to 30MHz)

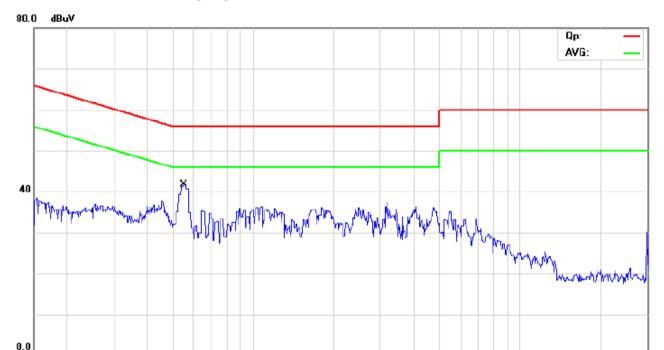
**EUT Operating Environment** 

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Charging Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



No. Mk.	Freq.	Reading Level		Measure- ment	Limit	Over		
	MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1 *	0.5556	26.30	11.43	37.73	56.00	-18.27	QP	
2	0.5556	3.40	11.43	14.83	46.00	-31.17	AVG	

(MHz)

5

30.000

0.5

0.150

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# B: Conducted Emission on Neutral Terminal (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Charging Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual

# 

No. Mk.	Freq.	Reading Level		Measure- ment	Limit	Over		
	MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1 *	0.5726	30.60	11.45	42.05	56.00	-13.95	QP	
2	0.5726	0.90	11.45	12.35	46.00	-33.65	AVG	

(MHz)

5

30.000

0.5

0.150

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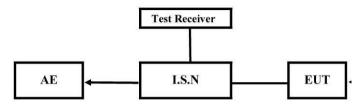
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# 4.2 Telecommunication ports Conducted Emission Test

#### 4.2.1 Schematics of the test

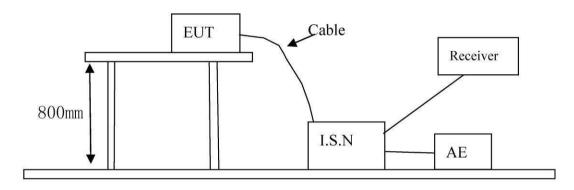


EUT: Equipment Under Test

#### 4.2.2 Test Method:

The test was performed in accordance with EN 55022: 2010+AC:2011

#### **Block diagram of Test setup**



#### 4.2.3 Telecommunication ports conducted Emission Limit

		Class A Limits				Class B Limits			
Frequency(MHz)	Quasi-peak Level		Quasi-peak Level Average Level		Quasi-peak Level		Average Level		
r requency(wiriz)	Vlotage	Current	Vlotage	Current	Vlotage	Current	Vlotage	Current	
	dB(uV)	dB(uA)	dB(uV)	dB(uA)	dB(uV)	dB(uA)	dB(uV)	dB(uA)	
$0.15 \sim 0.50$	97 to 87	53 to43	84 to74	40 to 30	84 to 74	40 to30	74 to64	30 to 20	
0.50 ~ 30.00	87	43	74	30	74	30	64	20	

Notes:

- 1. \*decreasing linearly with logarithm of frequency.
- 2. The tighter limit shall apply at the transition frequencies

#### 4.2.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak) and Average in the following diagram labelled as (QP)&AV

#### Remark:

Calculated measurement uncertainty=1.9dB

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#### A: Conducted Emission on Telecommunication port (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Normal operation mode** 

**Equipment Level: Class B** 

Results: N/A

Please refer to following diagram for individual

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# **B:** Conducted Emission on Telecommunication port (150kHz to30MHz)

**EUT Operating Environment** 

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Normal operation mode** 

**Equipment Level: ClassB** 

**Results: N/A** 

Please refer to following diagram for individual

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#### 4.3 Radiated Disturbance Test

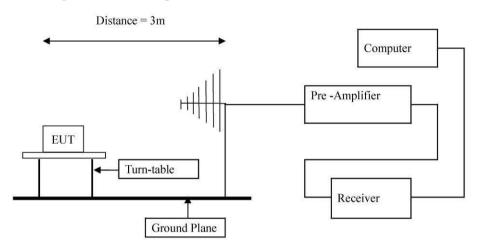
#### 4.3.1 Schematics of the test



#### 4.3.2 Test Method:

The test was performed in accordance with EN 55022: 2010+AC:2011

#### **Block diagram of Test setup**



#### 4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB µ V/m)					
	Class A Limits	Class B Limits				
30-230	50.00	40.00				
230-1000	57.00	47.00				

Note: The lower limit shall apply at the transition frequencies

# 4.3.4 Test result

Limits for Radiated Disturbance test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

#### Remark:

Calculated measurement uncertainty=4.7dB

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#### A: Radiated Disturbance (30MHz----1000MHz)

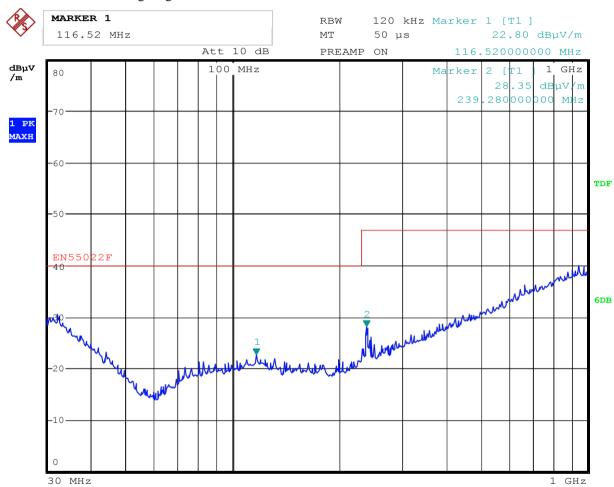
#### **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Charging Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.JUN.2016 10:46:19

Frequency (MHz)	Level@3m ( $dB\mu V/m$ )	Antenna Polarity	Limit@3m (dBµV/m)
116.520	22.80	Н	40.00
239.280	28.35	Н	47.00

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#### B: Radiated Disturbance (30MHz----1000MHz)

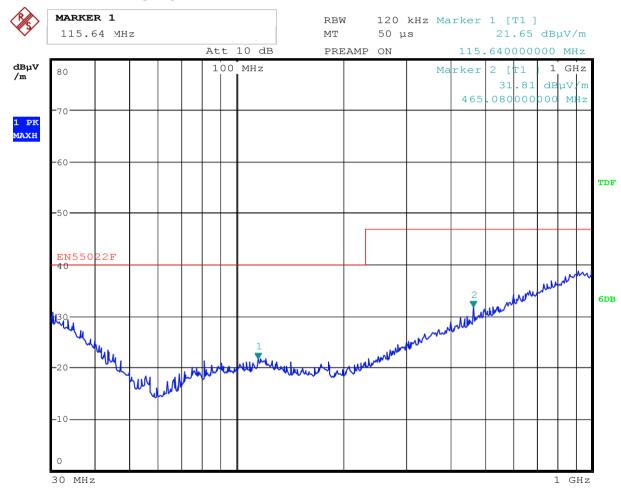
#### **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Charging Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.JUN.2016 10:43:33

Frequency (MHz)	Level@3m ( $dB\mu V/m$ )	Antenna Polarity	Limit@3m (dBµV/m)
115.640	21.65	V	40.00
465.080	31.81	V	47.00

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#### C: Radiated Disturbance (30MHz----1000MHz)

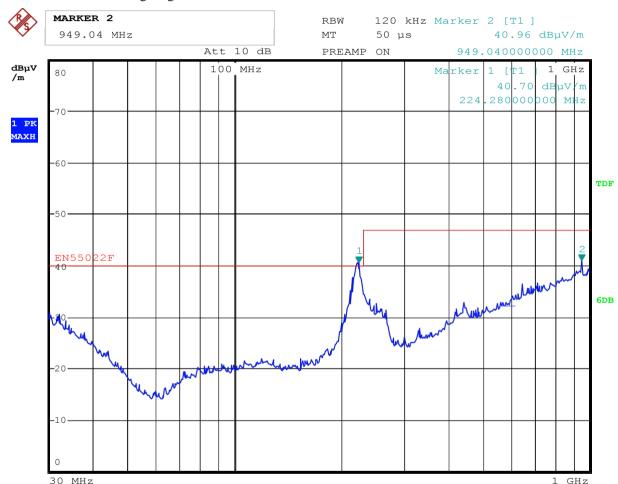
**EUT Operating Environment** 

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Discharge Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.JUN.2016 10:37:14

Frequency (MHz) Level@3m (dBµV/m)		Antenna Polarity	Limit@3m (dBµV/m)	
	949.040	40.96	Н	47.00
	224.280	40.70	Н	40.00

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#### D: Radiated Disturbance (30MHz----1000MHz)

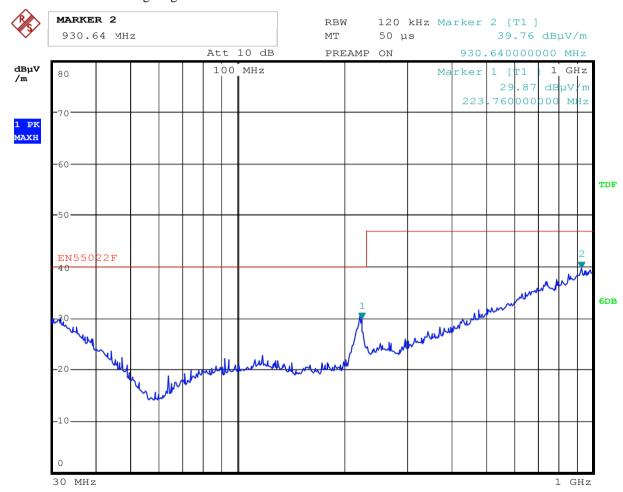
#### **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Discharge Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.JUN.2016 10:40:14

	Frequency (MHz)	Level@3m ( $dB\mu V/m$ )	Antenna Polarity	Limit@3m (dBµV/m)	
	930.640	39.76	V	47.00	
1	223.760	29.87	V	40.00	

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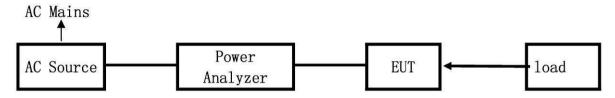
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#### 4.4 Harmonic Current Emission Test

#### 4.4.1 Schematic of the test



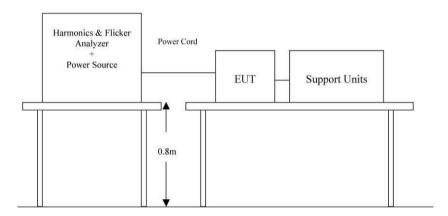
EUT: Equipment Under Test

#### 4.4.2 Test Method:

The test was performed in accordance with EN61000-3-2:2014

\*: The Level of the product is: CLASS D

#### **Block diagram of Test setup**



#### 4.4.3 Limits of Harmonic Current Emission For Class A

Harmonic order	Maximum permissible harmonic current
n	A
Odd ha	rmonics
3	2,30
5	1,14
7	0,77
9	0,40
11	0,33
13	0,21
$15 \leq n \leq 39$	0,15 1 <u>5</u>
Even ha	armonics
2	1,08
4	0,43
6	0,30
$8 \leq n \leq 40$	0,23 <u>8</u>

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#### 4.4.4 Test Results

Please refer to the following pages

**Harmonic Current Emission Test** 

**EUT Operating Environment** 

Temperature: 25 °C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

**EUT set Condition:** 

**Results: N/A** 

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		result/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

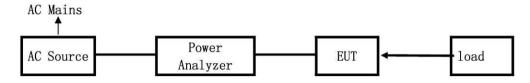
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# 4.5 Voltage Fluctuations & Flicker Test

#### 4.5.1 Schematic of the test

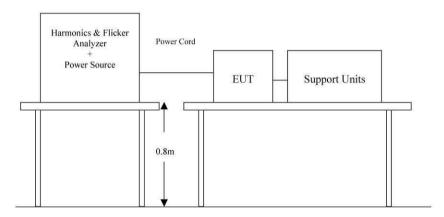


EUT: Equipment Under Test

#### 4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013

# **Block diagram of Test setup**



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#### 4.5.3 **Test Results**

Result: N/A

Please refer to following diagram for individual

#### Maximum Occurring Levels:

Ut: 230.1	(EUT	Test RMS	Voltage)

Pst:	Limit=	1.0	(The Highest short Term Flicker Value)
Plt:	Limit=	0.65	(The Highest Long Term Flicker Value)
dt(%):	Limit=	3.3%	(The Highest instantaneous Voltage Change (10ms))
dc(%):	Limit=	3.3%	(The highest Relative steady state voltage change (1sec))
dmax:	Limit=	4%	(The highest Max Relative voltage change)
Tdt:	Limit=	500ms	(The Max Time(in milli-sec) that dt exceeds 3%)

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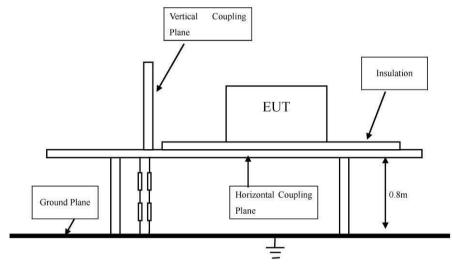
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#### 5.0 Immunity Test

# **5.1** Electrostatic Discharge

#### 5.1.1 Schematic of the test



#### 5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

#### 5.1.3 Test severity

- ±4Kv for direct & in-direct Contact Discharge
- ±8Kv for air Discharge

Performance Criterion Require: **B** (Please see following table)

#### 5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

#### Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (Kv)	discharge(Kv)
1	±2Kv	±2Kv
2	±4Kv	±4Kv
3	±6Kv	±8Kv
4	±8Kv	±15Kv

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#### 5.1.5 Test Result

# **EUT Operating Environment**

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
НСР	In-Direct	$\pm 2$ Kv, $\pm 4$ Kv	Pass
VCP	In-Direct	$\pm 2$ Kv, $\pm 4$ Kv	Pass
Shell (metal)	Contact Discharge	$\pm 2$ Kv, $\pm 4$ Kv	Pass
Screw	Contact Discharge	$\pm 2$ Kv, $\pm 4$ Kv	Pass
USB Port	Contact Discharge	$\pm 2$ Kv, $\pm 4$ Kv	Pass
Gap	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

**Remark:** Calculated measurement uncertainty= 0.2kV

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# 5.2 RF field strength susceptibility (80MHz----- 1000MHz)

#### 5.2.1 Schematics of the test



**EUT: Equipment Under Test** 

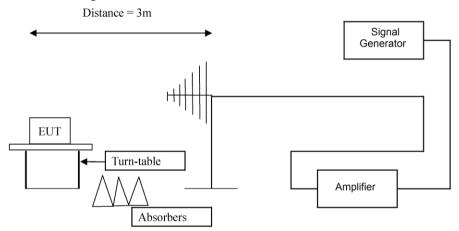
#### 5.2.2 Test Method:

The test was performed in accordance with EN 61000-4-3:2006

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

#### **Block diagram of Test setup**



# 5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

# **Severity Level**

Level	Field Strength (V/m)
1	1
2	3
3	10

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#### 5.2.4 Test Result:

# **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following table for individual results.

Frequency	Face	Polarity	Level	Dwell	Sweep	Results
(MHz)			(V/m)	Time(s)	Rate (%)	
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass

Remark: Calculated measurement uncertainty= 80MHz to 1000MHz (+3.7/ -1.3) V/m

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# 5.3 Electrical Fast Transient/Burst (EFT/B) immunitytest

#### 5.3.1 Schematics of the test



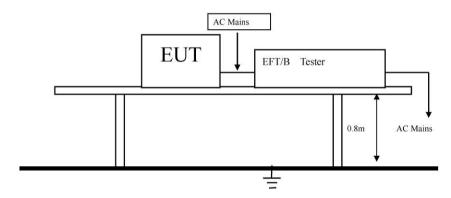
#### 5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: **B** (Please see following table)

#### **Block diagram of Test setup**



# 5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

#### Severity Level

	Open Circuit output Test Voltage	e ±10%
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

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#### 5.3.4 Test Results

# **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to following page.

Inject location: AC mains

Inject Line	Voltage kV	Inject Times (s)	Method	Results
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

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#### 5.4 Surge test

#### 5.4.1 Schematics of the test



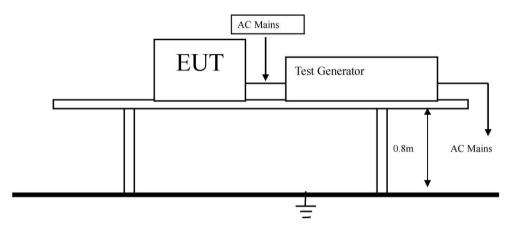
#### 5.4.2 Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

# **Block diagram of Test setup**



# 5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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# Severity Level

Severity Level	Open-Circuit Test Voltage		
	kV		
1	0.5		
2	1.0		
3	2.0		
4	4.0		
*	Special		

# 5.4.4 Test Results

# **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to following page.

Test location:

Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
	<u>±</u>	0	5	1.0	Pass
L-N	<u>±</u>	90	5	1.0	Pass
L-IN	<u>±</u>	180	5	1.0	Pass
	土	270	5	1.0	Pass

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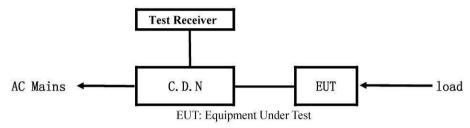
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#### 5.5 Conducted Immunity test

#### 5.5.1 Schematics of the test



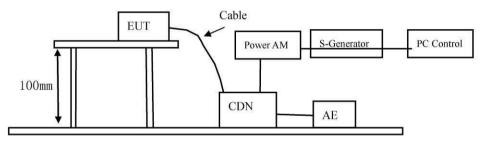
#### 5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2009

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

# **Block diagram of Test setup**



# 5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

#### Severity Level

Severity Level	Voltage Level (e.m.f) V		
1	1		
2	3		
3	10		
*	Special		

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# 5.5.4 Test Results:

# **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Frequency Range (MHz)	Injected Position	Strength	Criterion	Observation	Result
0.15 - 20	AC Line	3V (rms) Unmodulated	A	A	Pass
20 - 80	AC Line	3V (rms) Unmodulated	A	A	Pass

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## 5.6 Power-Frequency magnetic field test

## 5.6.1 Schematics of the test



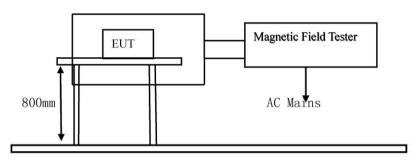
### 5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

# **Block diagram of Test setup**



# 5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description		
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.		
В	Degradation of performance allowed during the test the EUT returning intended operation after the test.		
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.		

### Severity Level

Severity Level	Magnetic Field Strength A/m		
1	1		
2	3		
3	10		
4	30		
5	100		
*	Special		

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## 5.6.4 Test Results:

# **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Test Level	Testing Duration	Coil Orientation	Criterion	Result
1A/m	5 Mins	X	A	N/A
1A/m	5 Mins	Y	A	N/A
1A/m	5 Mins	Z	A	N/A

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# 5.7 Voltage Dips/Interruptions immunity test

## 5.7.1 Schematics of the test

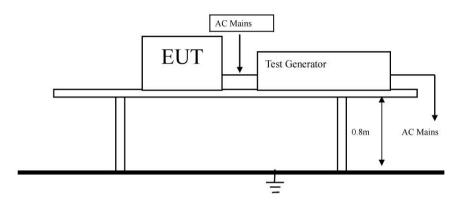


### 5.7.2 Test Method:

The test was performed in accordance with EN 61000-4-11:2004

Performance Criterion Require: C&B (Please see following table)

## **Block diagram of Test setup**



# 5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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# Severity Level

	Test Level %Ut	Reduction	Duration	Performance			
Voltage			(Periods)	Criteria			
Dip	<5	>95	0.5	В			
	70	30	25	C			
Voltage Interceptions	Test Level %Ut	Reduction	Duration	Performance			
			(Periods)	Criteria			
	<5	>95	250	C			

## 5.7.4 Test Result:

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Voltage Dip:

Test Level	Reduction	Duration	Phase Angle	Meet	Result
% Ut		(periods)		Criterion	
0	100	0.5	0° - 360°	A	Pass
70	30	25	0° - 360°	A	Pass

# Voltage Interceptions:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° - 360°	В	Pass

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# 6.0 Product Labelling

### **6.1** CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



**6.2** Mark Location: Rear enclosure

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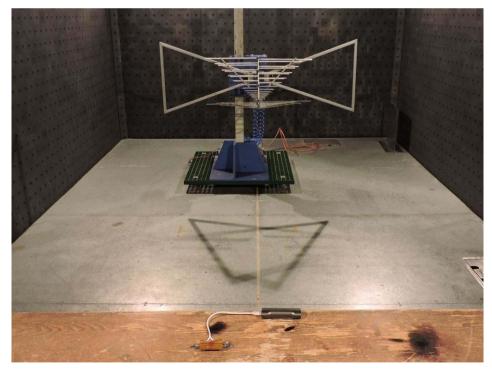
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# 7.0 Photo of testing





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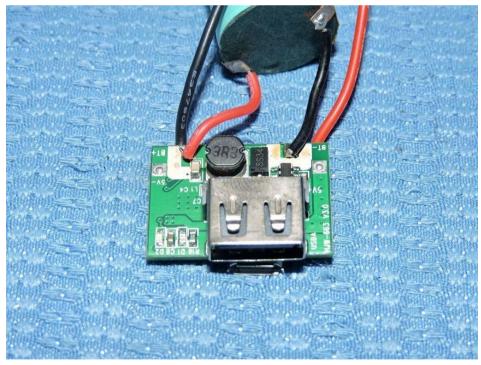
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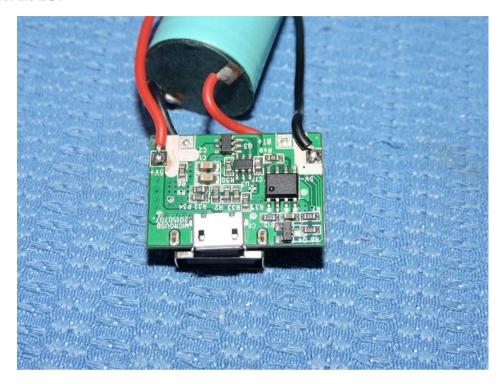


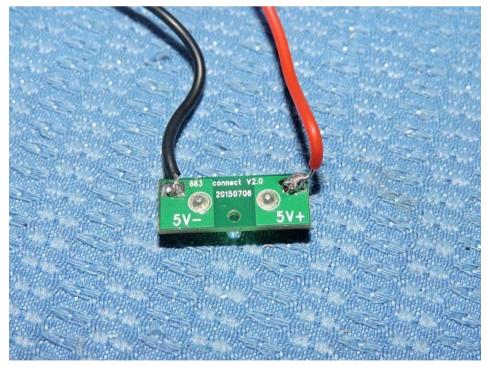
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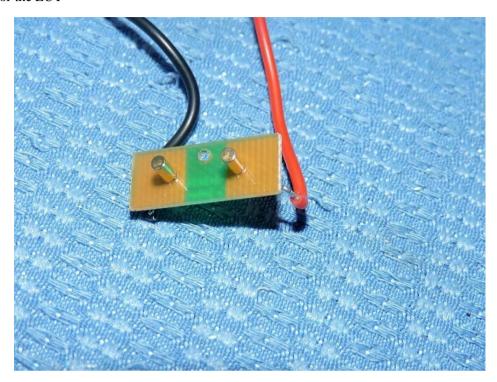


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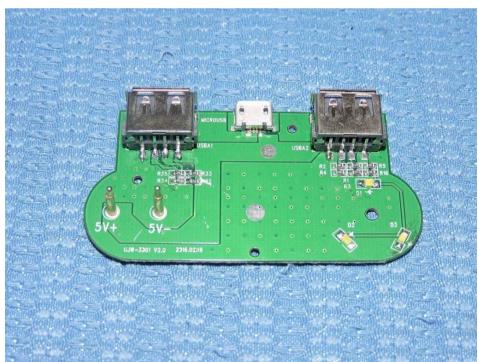
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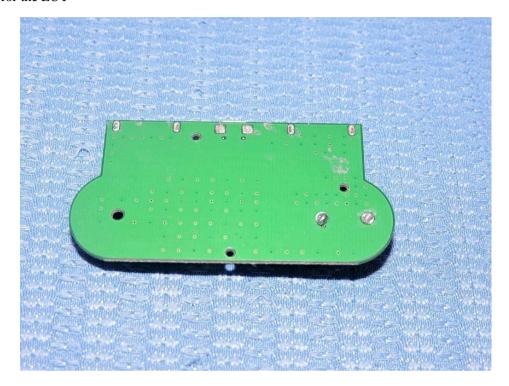




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-End of the report-